

REMARKS

Claims 1-28 are pending in the application.

At the outset, the Examiner is thanked for the thorough review and consideration of the pending application. The Final Office Action dated May 21, 2003 has been received and its contents carefully reviewed.

In the Office Action, claims 1, 10, and 11 are objected to for minor informalities. Applicants amend claims 1, 10, and 11 to correct minor errors, however, these amendments are for precision of language only and do not narrow the scope of the claims.

Claims 1-8, 11-20, and 23-28 are rejected under 35 U.S.C. § 102(b) as being anticipated by U.S. Patent No. 5,951,094 to Matsuoka et al. (hereinafter “Matsuoka”). Claims 9, 10, 21, and 22 are rejected under 35 U.S.C. § 103(a) as being unpatentable over Matsuoka and further in view of U.S. Patent No. 6,552,764 B2 to Fujioka et al. (hereinafter “Fujioka”) and U.S. Patent No. 6,486,930B1 to Oh-kyong Kwon (hereinafter “Oh-kyong Kwon”).

The rejection of independent claim 1 is respectfully traversed and reconsideration is requested. Claim 1 is allowable over the cited references in that this claim recites a combination of elements including, for example, “a first substrate having a groove around a display area; [and] a second substrate having a ridge that extends into the groove”.

None of the cited references, including Matsuoka, Fujioka, and Oh-kyong Kwon, singly or in combination, teaches or suggests at least this feature of the claimed invention. The structure of claim 1 of the present invention is different from the Matsuoka structure in that the present invention relates to a structure for capturing liquid crystal runoff during the manufacturing process, whereas Matsuoka relates to preventing corrosion of wiring around a substrate.

The Examiner relies solely on Matsuoka to disclose the “groove” and “ridge” of the claims. However, Matsuoka clearly does not teach, disclose, or suggest either of these features. For example, reference numeral 20, cited by the Examiner as disclosing the “groove” of the claims, is not, in fact, a groove at all. Rather, reference numeral 20 refers to a contact pad (Matsuoka, column 4, lines 15-31). In addition, element 20 is not “around a display area” as required by the claims. Because 20 is a contact pad, it is not around anything (Matsuoka, Fig. 7A and column 4, lines 29-31).

Furthermore, element 21 in Figs 7A-C does not disclose the “ridge” of the claim, contrary to the assertion of the Examiner. Fig. 7B clearly shows that element 21 is not a ridge. Element 21 is a conductive material that connects contact pad 20 to electrode 17 (Matsuoka, column 4, lines 15-25).

Because Matsuoka does not disclose or suggest these features of the claim, and because the Examiner, by relying solely on Matsuoka to show the “groove” and “ridge” of the claim, implicitly acknowledges that Fujioka and Oh-kyong Kwon do not disclose them, independent claim 1 is allowable over the prior art at least for these reasons.

Accordingly, Applicant respectfully submits that claim 1, and claims 2-10, which depend from claim 1, are allowable over the cited references.

The rejection of independent claim 11 is respectfully traversed and reconsideration is requested. Claim 11 is allowable over the cited references in that this claim recites a combination of elements including, for example, “a first patterned material on said first substrate, said first pattern material having a groove around said display predetermined area; a second substrate adjacent said first substrate; a second patterned material on said second substrate, said second patterned material having a ridge that extends into said groove”.

None of the cited references, including Matsuoka, Fujioka, and Oh-kyong Kwon, singly or in combination, teaches or suggests at least this feature of the claimed invention. The structure of claim 11 of the present invention is different from the Matsuoka structure in that the present invention relates to a structure for capturing liquid crystal runoff during the manufacturing process, whereas Matsuoka relates to preventing corrosion of wiring around a substrate.

As discussed above, Matsuoka does not disclose or suggest the “groove” or “ridge” of the claim. In addition, the Examiner, by relying solely on Matsuoka to show the “groove” and “ridge” of the claim, implicitly acknowledges that Fujioka and Oh-kyong Kwon do not disclose them. Therefore, independent claim 11 is allowable of the cited references.

Accordingly, Applicant respectfully submits that claim 11, and claims 12-13 which depend from claim 11, are allowable over the cited references

The rejection of independent claim 14 is respectfully traversed and reconsideration is requested. Claim 14 is allowable over the cited references in that this claim recites a combination of elements including, for example, “(a) forming a first substrate with a groove around a display region; (b) forming a second substrate with a ridge that can fit into the groove”.

None of the cited references, including Matsuoka, Fujioka, and Oh-kyong Kwon, singly or in combination, teaches or suggests at least this feature of the claimed invention. The structure of claim 14 of the present invention is different from the Matsuoka structure in that the present invention relates to a structure for capturing liquid crystal runoff during the manufacturing process, whereas Matsuoka relates to preventing corrosion of wiring around a substrate.

As discussed above, Matsuoka does not disclose or suggest the “groove” or “ridge” of the claim. In addition, the Examiner, by relying solely on Matsuoka to show the “groove” and “ridge” of the claim, implicitly acknowledges that Fujioka and Oh-kyong Kwon do not disclose them. Therefore, independent claim 14 is allowable of the cited references.

Accordingly, Applicant respectfully submits that claim 14, and claims 15-23 which depend from claim 14, are allowable over the cited references.

The rejection of independent claim 24 is respectfully traversed and reconsideration is requested. Claim 24 is allowable over the cited references in that this claim recites a combination of elements including, for example, “(b) forming a first patterned material on the first substrate, wherein the first patterned material includes a groove around the array area; (c) forming color filters on a second substrate; (d) forming a second patterned material on the second substrate, wherein the second patterned material includes a ridge dimensioned to align with the groove”.

None of the cited references, including Matsuoka, Fujioka, and Oh-kyong Kwon, singly or in combination, teaches or suggests at least this feature of the claimed invention. The structure of claim 24 of the present invention is different from the Matsuoka structure in that the present invention relates to a structure for capturing liquid crystal runoff during the manufacturing process, whereas Matsuoka relates to preventing corrosion of wiring around a substrate.

As discussed above, Matsuoka does not disclose or suggest the “groove” or “ridge” of the claim. In addition, the Examiner, by relying solely on Matsuoka to show the “groove” and “ridge” of the claim, implicitly acknowledges that Fujioka and Oh-kyong Kwon do not disclose them. Therefore, independent claim 24 is allowable of the cited references.

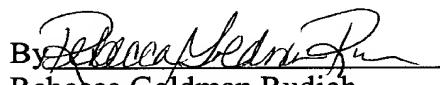
Accordingly, Applicant respectfully submits that claim 24, and claims 25-28 which depend from claim 24, are allowable over the cited references.

If for any reason the Examiner finds the application other than in condition for allowance, the Examiner is requested to call the undersigned attorney at (202) 496-7500 to discuss the steps necessary for placing the application in condition for allowance. All correspondence should continue to be sent to the below-listed address.

If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. §1.136, and any additional fees required under 37 C.F.R. §1.136 for any necessary extension of time, or any other fees required to complete the filing of this response, may be charged to Deposit Account No. 50-0911. Please credit any overpayment to deposit Account No. 50-0911. A duplicate copy of this sheet is enclosed.

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Respectfully submitted,

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